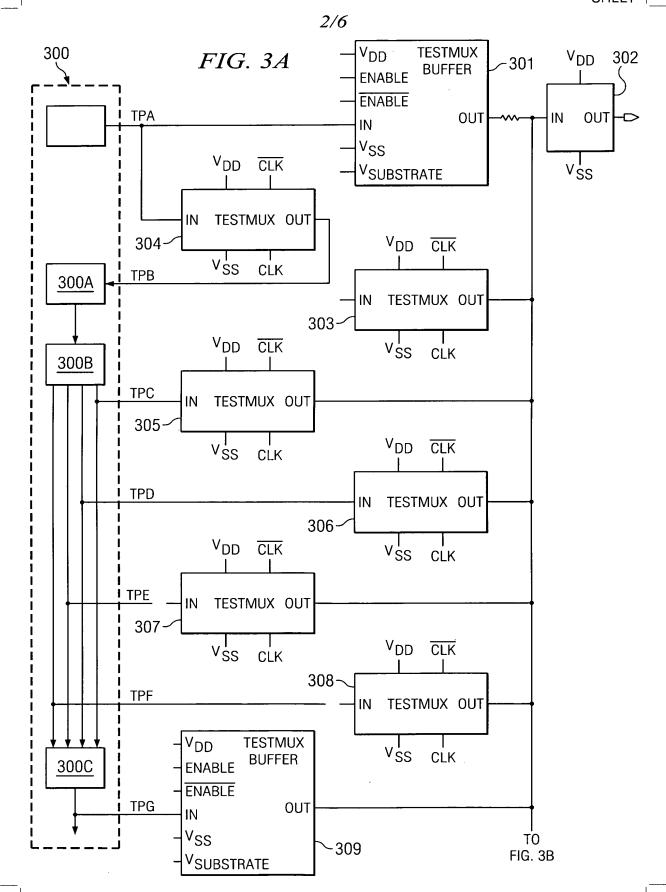
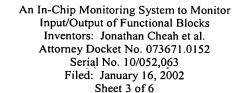
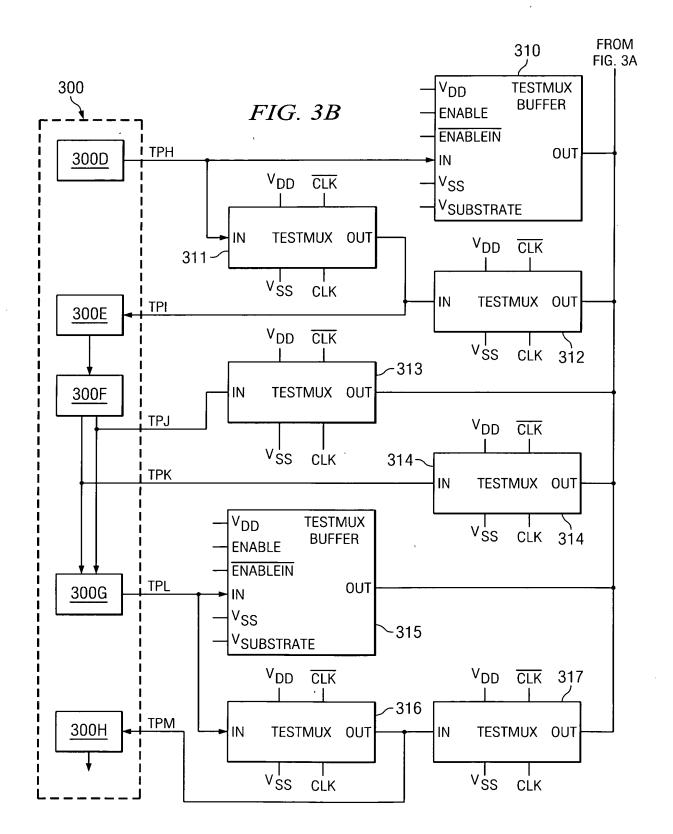
An In-Chip Monitoring System to Monitor Input/Output of Functional Blocks Inventors: Jonathan Cheah et al. Attorney Docket No. 073671.0152 Serial No. 10/052,063 Filed: January 16, 2002 Sheet 1 of 6 REPLACEMENT SHEET 1/6 FIG. 1 FIG. 2 103 105 101 100 CONTROL WORD **TEST** 213 -201**GENERATOR** PAD -215 215A--203 **TESTMUX** 109 107 111 200 215 217-219 FIG. 6 600 601-209 **START** 207 211 ATTACH A TEST PAD AND A PLURALITY OF ELECTRICAL 602-COMPONENTS TO A SURFACE OF FIG. 5 500 A SUBSTRATE 501-**START** COUPLE A TEST COMPONENT OF THE PLURALITY OF ELECTRICAL 603 502-COMPONENTS TO A TRANSMISSION GENERATOR CODE WORD GATE ATTACHED TO THE SURFACE OF THE SUBSTRATE **ROUTE CODE WORD** 503-TO LOGIC BLOCK COUPLE THE TRANSMISSION 604 GATE TO THE TEST PAD PROCESS CODE WORD AND DETERMINE WHICH TRANSMISSION 605-TEST THE CIRCUIT GATES TO TURN ON OR OFF TO 504-TRANSFER A SIGNAL FROM AN TRANSMIT A CODE WORD TO A ELECTRICAL COMPONENT LOGIC BLOCK ASSOCIATED WITH UNIQUELY ASSOCIATED WITH THE THE TRANSMISSION GATE, THE CODEWORD TO A TEST PAD 606-CODE WORD UNIQUELY ASSOCIATED WITH THE TEST **ROUTE SIGNAL TO TEST PAD** COMPONENT 505-RECEIVE A SIGNAL FROM ANALYZE SIGNAL USING A 607-THE TEST COMPONENT SIGNAL ANALYZER COUPLED 506 TO THE TEST PAD RELAY SIGNAL TO THE TEST PAD 608-YES REPEAT? ANALYZE SIGNAL USING A SIGNAL ANALYZER COUPLED 609-5**0**7 . NO TO THE TEST PAD **END** 508-**END** 610An In-Chip Monitoring System to Monitor Input/Output of Functional Blocks Inventors: Jonathan Cheah et al. Attorney Docket No. 073671.0152
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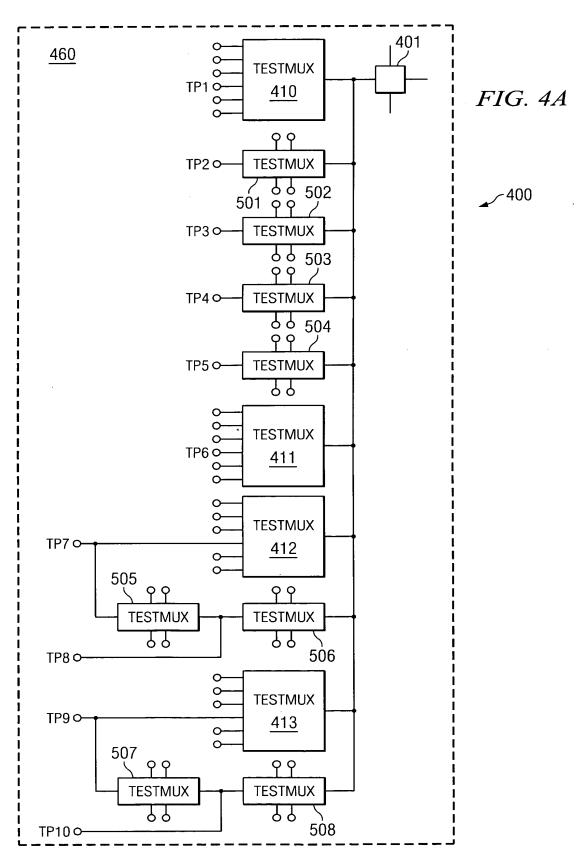




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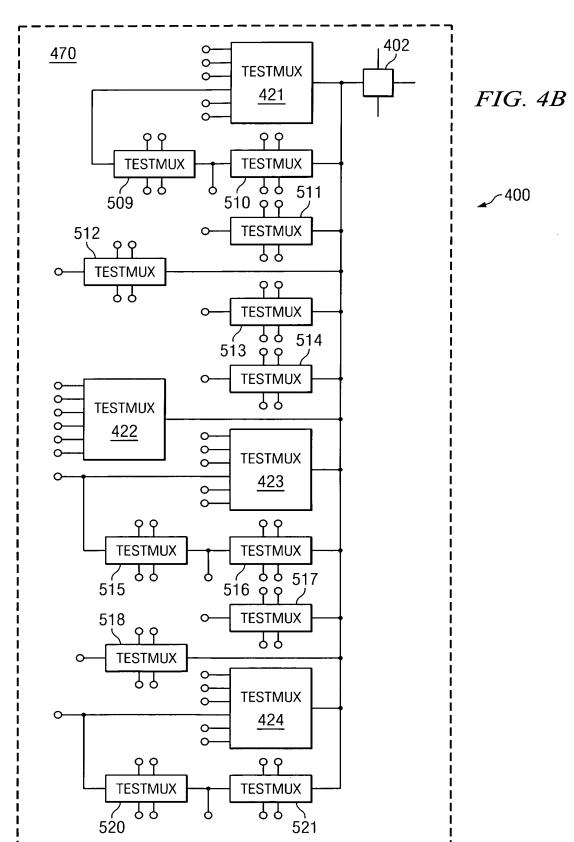


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